

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Substitute for form 1449/PTO)

 ATTY. DOCKET NO.  
**044117-0143**

 SERIAL NO.  
**10/539,771**

 APPLICANT  
**Eric PINET, et al.**

 FILING DATE  
**January 10, 2006**

 GROUP  
**1797**

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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						Yes	No

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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